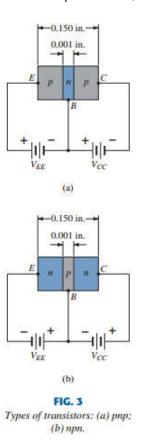
Chapter 3, Bipolar Junction Transistors (BJTs)

3.2 Transistor construction

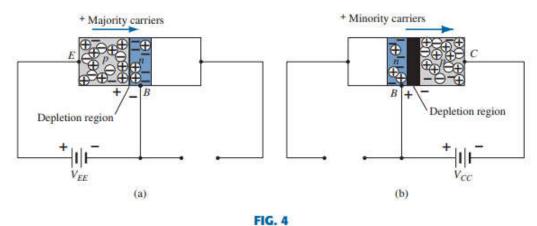
A transistor is a 3-layer semiconductor device containing either 2 n- and 1 p-type layers, or 2 p- and 1 n-type material. The former is called an npn transistor, and the latter a pnp transistor. Both are shown in fig 3 with proper dc biasing. The dc biasing is necessary to establish a proper region of operation for ac amplification. The emitter layer is heavily doped, and the base and collector only lightly doped. The outer layers have widths much greater than the sandwiched p- or n-type material. The sandwiched layer is also less doped than outer layers (typically 1:10 or less). The lower doping levels decrease conductivity by limiting the free carriers. For the biasing in fig 3 the terminals have been indicated with E for emitter, C for collector and B for base. The term *bipolar* in BJTs reflects the fact that holes and electrons participate in the injection process in the oppositely polarized material. If only 1 carrier is used, it's considered a *unipolar* device, such as the Schottky diode.



3.3 Transistor operation

The basic operation of a pnp transistor of fig 3a will be described. The working of an npn transistor is exactly the same if the roles of electrons and holes are reversed. Fig 4a has a redrawn pnp transistor without the base-to-collector bias. The depletion region has reduced in width due to the applied bias, resulting in a heavy flow of majority carriers from p- to n- type material. We now remove the base-to-emitter bias as shown in 4b. Notice how similar this is to that of a reverse-biased diode. Recall that the flow of majority carriers is 0, resulting in only a minority carrier flow, as shown in fig 4b. In summary, **One p-n junction of a transistor is reverse-biased, while the**

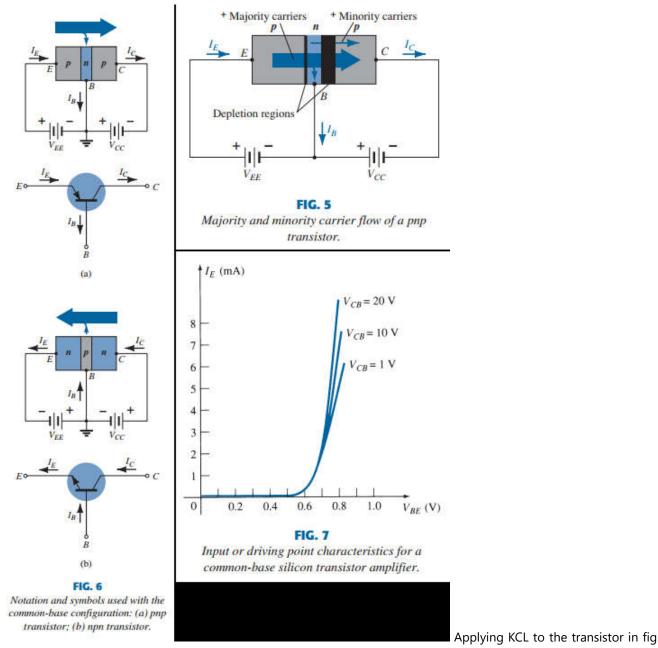
other is forward-biased



Biasing a transistor: (a) forward-bias; (b) reverse-bias.

In fig 5 both biasing potentials have been applied to a pnp transistor, with the resulting carrier flows indicated. See the width of the depletion region, indicating clearly which junction is forward- or reverse-biased. as shown in fig 5, a large number of majority carriers will diffuse across the forward-biased p-n junction into the n-type material. Since the sandwiched n-type material is very thin and a low conductivity, a small number of these carriers will take the path of high resistance to the base terminal. The magnitude of I_B is on the order of a few μA , compared to the mA for the I_E, I_C . The larger numbers of these majority carriers will diffuse across the reverse-biased junction to the p-type connected to the collector terminal, as shown in fig 5. The reason for the east with which the majority carriers can cross the reverse-biased junction is easily explained if we remember that for the reverse-biased diode, the injected majority carriers will appear as minority carriers in the n-type material. In other words, there has been an injection of minority carriers in the n-type region material. Combining this with the fact that all the minority carriers in the depletion region will cross the reverse-biased junction of a

diode accounts for the flow as shown in fig 5.



5 as if it is a single node, we get

$$I_E = I_C + I_B$$
 (1)

The I_C , however, comprises of 2 components, the majority and minority carriers as shown in fig 5. The minority current component is called the *leakage current*, $I_{CO}(I_C$ current with emitter terminal Open). The I_C is determined by

For general purpose transistors, I_C is measured in mA, and I_{CO} in $\mu A, nA.I_{CO}$, like I_s for a reverse-biased diode, is temperature sensitive and must be examined when applications of wide temp. ranges are considered, since it can severely affect the stability of a system at high temps. Improvements have resulted in significantly lower I_{CO} where

the effects can be ignored

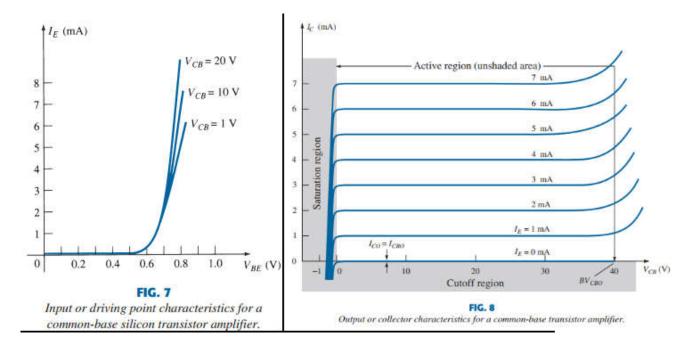
3.4 Common-base config

The notation used with the majority of texts is indicated in fig 6 for the common-base config for pnp and npn. The common-base terminology is derived from the fact that the base is common to both the input and output sides of the config. Also, the base is usually the terminal at or closest to the ground potential, this text will refer conventional (hole) flow when indicating current directions. The result is that the arrows in all electronic symbols have a direction defined by this convention.

The arrow in the graphic symbol defines the direction of emitter current (conventional flow) through the device

Note that in each case, eq 1 is satisfied. Note also that the applied V sources are such as to establish current in the direction indicated. That is, compare the direction of I_E, V_{EE} and the direction of I_C, V_{CC} . To fully describe the behavior of a 3-terminal device such as the common-base amplifiers of fig 6 requires 2 sets of characteristics, one for the *driving point or input parameters* and the other for the *output* side. The input set for the common-base amp as shown in fig 7 relates an input current I_E to an input voltage V_{BE} for various levels of output voltage V_{CB}

The output relates an output current I_C to an output voltage V_{CB} for different levels of input current I_E as shown in fig 8. The output or *collector* set of characteristics has 3 basic regions of interest, the *active*, *cutoff and saturation regions*. The active region is normally employed for linear (undistorted) amplifiers. In particular, In the active region, B-E junction is forward biased, while C-B junction is reverse-biased



The active region is defined by biasing arrangements of fig 6. At the lower end of the active region, $I_E=0$, and the collector current is simply the reverse saturation current I_{CO} , as indicated in fig 9. The current I_{CO} is so small that it appears on virtually the same horizontal line as $I_C=0$. The circuit conditions that exist when $I_E=0$ for the common-base config are shown in fig 9. The notation commonly used for I_{CO} on data- or spec sheets is I_{CBO} (collector-to-base with emitter Open). Usually, this is so low that the effect can be ignored. However, for high power units, I_{CBO} will still be in the μA range, and is still temp. sensitive, so it may become an important factor at high temps, since it increases rapidly. Note in fig 8 that as I_E increases above zero, the I_C increases to a magnitude

about equal to that of I_E as determined by the basic transistor-current relations. See also the almost negligible effect of V_{CB} on the collector current for the active region. The curves indicate that a first approximation for the relation between I_E , I_C in the active region is



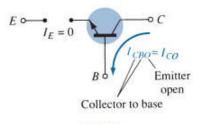


FIG. 9
Reverse saturation current.

As inferred by the name, the cutoff region is defined as that region where the collector current is 0A, as shown in fig 8. In addition, In the cutoff region the base-emitter and collector-base junctions are both reverse-biased

The saturation region is defined as the region of characteristics to the left of $V_{CB}=0V$. The horizontal scale in this region is expanded to clearly show the dramatic change in characteristics in this region. See the exponential increase in I_C as V_{CB} increases towards 0V.

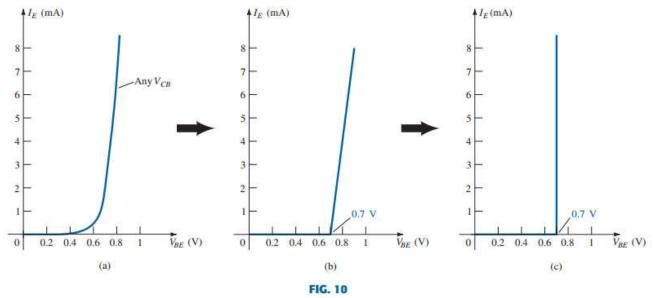
In the saturation region, base-emitter and collector-base junctions are forward biased

The input characteristics of fig 7 reveal that for fixed values of collector Voltage V_{CB} , as the base-to-emitter voltage increases, I_E increases in a manner that resembles a that of a diode. In fact, increasing V_{CB} has such a small effect on characteristics drawn as shown in fig 10a. If we apply the piecewise-linear approach, the characteristics of fig 10b result. Taking it a step further and ignoring the slope of the curve, and therefore the resistance associated with the forward-biased junction, results in characteristics in fig 10c. For the analysis to follow, the equivalent model of fig 10c will be used for all the dc analysis of transistor networks. That is, once a transistor is on,

$$V_{BE}pprox 0.7V$$
 (4)

In other words, the effect of variations due to V_{CB} and the slope of input characteristics will be ignored, as we want to analyze transistor networks such that they provide a good approximation to the actual response without too much calculations.

It's important to fully appreciate the statement made by fig 10c. They say that with the transistor being "on" (being in the active stage), the V_{BE} will be at 0.7 V for any level of I_E as controlled by the network. In fact, when encountering any transistor config in dc mode, one can immediately specify that $V_{BE}=0.7V$, if the device is in the active region.



Developing the equivalent model to be employed for the base-to-emitter region of an amplifier in the dc mode.

Alpha (α)

DC MODE In dc mode the levels of I_C , I_E due to majority carriers related by a quantity called alpha is defined by the following:

$$lpha_{dc} = rac{I_C}{I_E}$$
 (5)

Where I_C, I_E are the current levels at point of operation. Eventho the characteristics of fig 8 would suggest that $\alpha=1$, for practical devices it's typically between 0.9 and 0.998, with most values being at the higher end of the range. Since alpha is defined only by the majority carriers, eq 2 becomes

$$I_C = \alpha I_E + I_{CBO}$$
 (6)

For the characteristics of fig 8 when $I_E=0mA$, $I_C=I_{CBO}$, but it's usually so small it's virtually undetectable on the graph. In other words, when $I_E=0mA$, $I_C\approx 0mA$

AC MODE

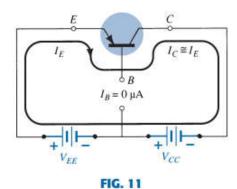
For ac situations where the point of operation moves on a curve, alpha ac is defined by

$$lpha_{ac} = \left. rac{\Delta I_C}{\Delta I_E}
ight|_{V_{CB} = constant}$$
 (7)

The ac alpha is formally called the *common-base, short-circuit, amplification factor*. Most of the time, $\alpha ac \approx \alpha dc$, allowing one to substitute one for the other. The use of EQ 7 will be shown in section 6.

Biasing

The proper biasing of the common-base config in the active region can be determined quickly by $I_C \approx I_E$ and assuming $I_B \approx 0 \mu A$. The result is the config of fig 11 for the pnp transistor. The arrow defines the direction of current, the dc supplies are placed with the polarity that'll support that. for npn the directions are reversed. A quick mnemonic is NPN (Not Pointing iN), PNP(Pointing iN)



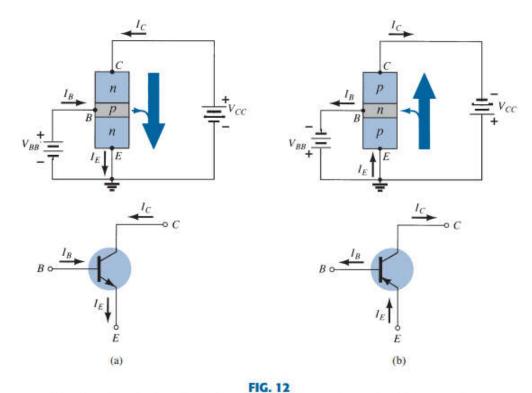
Establishing the proper biasing management for a common-base pnp transistor in the active region.

Breakdown Region

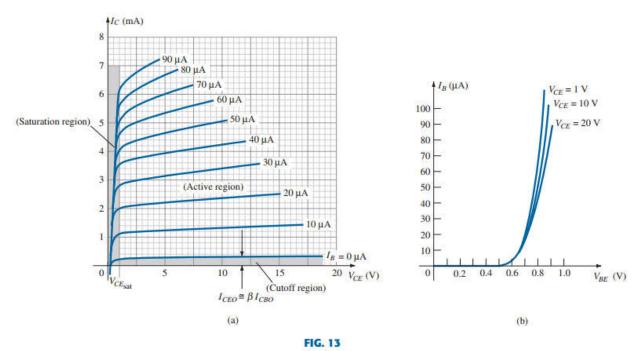
As V_{CB} goes up, there's a point where the curve goes up dramatically in FIG 8. This is due to an avalanche effect where reverse-bias V reaches the breakdown region. As stated earlier, the B*C junction is reverse-biased in the active region, but there's a point where the voltage will reach the avalanche effect. This results in a large increase in current for a small increase in V_{BC} . The largest base-to-collector voltage is labeled BV_{CBO} as shown in FIG 8, sometimes referred to as $V_{(BR)CBO}$ as shown in FIG 23. note in each of the notations, the O refers to the E being open. Very important to remember that this is only for the common-base config. In the common-emitter config the limiting V is quite less.

3.5 Common-emitter config

The most frequently found transistor config can be seen in FIG 12, for pnp and npn. It's called the *common-emitter* config because the emitter is common to both the input and output terminals(B and C terminals here). 2 sets of characteristics are again needed to describe the behavior of the common-emitter fully: One for the input or base-emitter circuit, and one for the output or collector-emitter circuit, both shown in fig 13.



Notation and symbols used with the common-emitter configuration: (a) npn transistor; (b) pnp transistor.



Characteristics of a silicon transistor in the common-emitter configuration: (a) collector characteristics; (b) base characteristics.

Eventho the transistor config has changed, the same current relations apply ($I_E=I_C+I_B,I_C=\alpha I_E$). For the common-E config the output characteristics are a plot of the output current I_C versus the output V V_{CE} for a range of values of input current I_B . The input characteristics Are a plot of the input current I_B versus the input V V_{BE} for a range of output V V_{CE} . Note that on the characteristics of FIG 14 the magnitude of $I_B\approx \mu A,I_C\approx mA$. Consider that the curves of I_B aren't as horizontal as those obtained for I_E in the common-B config, indicating that he V_{CE} will be influenced by the magnitude of the I_C . The active region for the common-E config is that portion of the upper-right region that has the greatest linearity(where I_B is nearly straight). In FIG 14a this region is to the right

of the vertical dashed line at V_{CEsat} and above $I_B \approx 0$. The region to the left of V_{CEsat} is the saturation region.

In the active region of the common-e amplifier, the BE junction is forward-biased, while the CB junction is reverse-biased You'll recall that these were the same conditions in the active region of common-B config. The active region fo the common-E config can be employed for V, I or P amplification. The cutoff region for common-E config is not as well defined as that of the common-B config. Note on the c characteristics of FIG 14 that $I_C \neq 0 \forall I_B = 0$. For the common-B config, when the input current $I_E = 0$, $I_C I_{CO}$, so that the curve $I_E = 0$ and the voltage axis were practically one. The reason for this difference in C characteristics can be derived through manipulation of EQ 3 and 6. that is:

$$I_{C} = \alpha I_{E} + I_{CBO}$$

$$I_{C} = \alpha (I_{C} + I_{B}) + I_{CBO}$$

$$I_{C} = \frac{\alpha I_{B}}{1 - \alpha} + \frac{I_{CBO}}{1 - \alpha}$$

$$(8)$$

If we consider the case discussed above, where $I_B=0A$ and substitute lpha=0.996, the result is

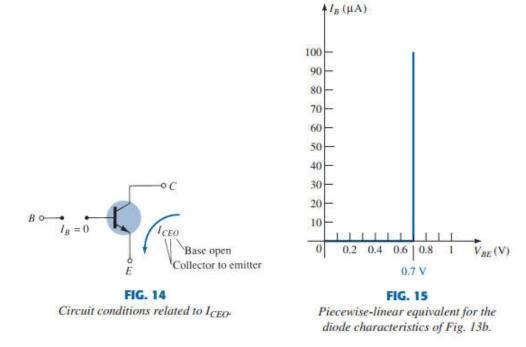
$$I_C = rac{lpha(0A)}{0.004} + rac{I_{CBO}}{0.004} \ = rac{I_{CBO}}{0.004} = 250I_{CBO}$$

If $I_{CBO}=1\mu A$, the resulting I_C with $I_B=0A$ would be 0.25 mA, as shown in fig 14. For future reference, the I_C is defined by the condition $I_B=0\mu A$ will be indicated by the following equation:

$$I_{CEO} = rac{I_{CBO}}{1-lpha}igg|_{I_B=o\mu A}$$
 (9)

In Fig 13, the conditions surrounding this newly defined current are demonstrated with it's assigned reference direction. For Linear amplifier purposes, the cutoff for the common-E config will be defined by $I_C=I_{CEO}$

In other words, the region below $I_B=0\mu A$ is to be avoided when undistorted output is required. When used as a switch in the logic circuitry of a computer, a transistor has 2 points of operation of interest: one in the cutoff and one in the saturation region.



The cutoff condition should ideally be $I_C=0mA$ for the chosen V_{CE} . Since I_{CEO} is typically low for silicon, cutoff will exist for switching purposes when $I_B=0\mu A or I_C=I_{CEO}$ for silicon transistors only. For Ge transistors, cutoff for switching purposes will be defined as those conditions where $I_C=I_{CBO}$. This condition can normally be obtained for Ge transistors by reverse-biasing the BE junction to 0.1 V. Recall that for the common-B config that the input set of characteristics was approximated by a straight line that resulted in $V_{BE}=0.7V$ for any level of $I_E>0mA$. For the common-E config the same approach applies, resulting in fig 15. The result supports our earlier conclusion that for a transistor in the on or active region the $V_{BE}=0.7V$, for any level of I_B

Beta (β)

DC MODE In DC mode the levels of I_C , I_B are related by a quantity called beta and defined as follows:

$$eta_{dc} = rac{I_C}{I_B}$$
 (10)

where I_C, I_B are determined at a particular operating point. Practically, $\beta \in [50, 400]$, with most in the midrange. as for α, β reveals the relative magnitude of one current with respect to another. For a device with a $\beta = 200$, the $I_C = 200I_B$. On spec sheets, B_{dc} is usually indicated as h_{FE} (hybrid equivalent circuit, forward-current amplification and common-E config)

AC MODE For ac situations, ac beta is defined as

$$eta_{ac} = \left. rac{\Delta I_C}{\Delta I_B}
ight|_{V_{CE}=constant}$$

The formal name for it is common-E, forward-current, amplification factor. Since the I_{C} is usually the output current

for common-E configs, and I_B is the input current, the term amplification is included in the nomenclature. EQ 11 is similar to that of α_{ac} in section 4. The procedure for obtaining the alpha from characteristic curves was not described because of the difficulty of actually measuring changes in I_C , I_E . EQ 11 can be described with clarity, and can be used to find the alpha using an equation. On spec sheets, $B_{ac}=h_{fe}$ usually. The use of EQ 11 is est describes with a numerical example, such as characteristic in fig 13a and 17. Determining B_{ac} for a region of characteristics defined by operating point of $I_B=25\mu A, V_{CE}=7.5V$ as in fig 16. The restriction of $V_{CE}=$ constant requires a vertical line drawn through the operating point $V_{CE}=7.5V$. The ΔI_B as shown in EQ 11 is then defined by choosing 2 points on either side of the Q-point along the vert. axis about equal distance to either side. for this situation, $I_B=20\mu A, 30\mu A$ is decent.

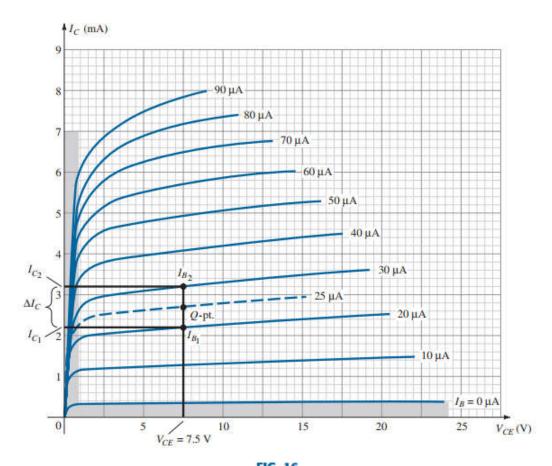


FIG. 16

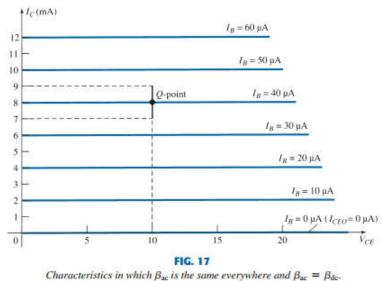
Determining β_{ac} and β_{dc} from the collector characteristics.

They also define levels

of I_B that are easily defined rather than requiring interpolation of the level between curves. Keep the δI_B as small as possible. At the 2 intersections and the vertical axis, the 2 levels of I_C can be determined by drawing a horizontal line over to the vert. axis and reading the resulting I_C vals. The resulting beta can then be determined by

$$egin{aligned} eta_{ac} &= rac{\Delta I_C}{\Delta I_B}igg|_{V_{CE}=constant} \ &= rac{3.2mA-2.2mA}{30\mu A-20\mu A} = rac{1mA}{10\mu A} \ &= 100 \end{aligned}$$

The solution above reveals that for an ac input at B, the $I_C pprox 100 I_B$. When using the dc beta at Q-point, we get $eta_{dc}=rac{I_C}{I_B}=108$, which is close enough to be used interchangeably most of the time. Generally, the smaller the I_{CEO} , the more valid the approximation is. If the characteristics are approximated by those in fig 17, the level of eta_{ac} would be the same in every region. Note that each $\Delta I_B=10\mu A, \Delta I_C=2mA$, so $eta_{ac}=200$, and $eta_{dc}=200$



when calculated as well.

Although a true set of transistor characteristics will never look exactly like FIG 17, it does provide a set of characteristics for comparison with those from a tracer. For the following analysis, we will use β w/o subscript. A relationship can be developed between β, α using basic relationships introduced so far. Using

$$eta = rac{I_C}{I_B} \leftrightarrow I_B = rac{I_C}{eta} \ lpha = rac{I_C}{I_E} \leftrightarrow I_E = rac{I_C}{lpha}$$

Substituting into

$$egin{aligned} I_E &= I_C + I_B \ rac{I_C}{lpha} &= I_C + rac{I_C}{eta} \ & ext{dividing both sides by} I_C \ rac{1}{lpha} &= 1 + rac{1}{eta} \end{aligned}$$

In the end,

$$lpha = rac{eta}{eta + 1} or \ eta = rac{lpha}{1 - lpha}$$

(12,13)

In addition, recall that $I_{CEO}=rac{I_{CBO}}{1-lpha}\equivrac{1}{1-lpha}=eta+1$ derived from above, we find that $I_{CEO}=(eta+1)I_{CBO}$ or

$$I_{CEO} pprox eta I_{CBO}$$
 (14)

Beta is particularly important because it provides a link between current levels of input and output circuits for a common-E config. That is,

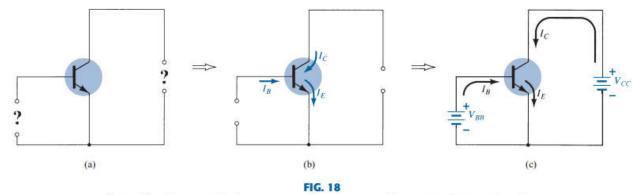
$$I_C = \beta I_V$$
 (15)

and with some manipulation, we get

$$I_E = (eta+1)I_B$$
 (16)

Biasing

The proper biasing of a common-E amplifier can be determined the same way as that of common-B. Let's assume we are presented with an npn transistor as shown in FIG 18a and asked to apply th proper biasing to place the device in the active region. The first step is to indicate the direction of I_E as established by the arrow in the symbol. Next, the other currents are introduced keeping in mind KCL and $I_C + I_B = I_E$. Finally, the voltages are introduced with polarities that'll support those current directions. The same for pnp transistors, just everything reversed.



Determining the proper biasing arrangement for a common-emitter npn transistor configuration.

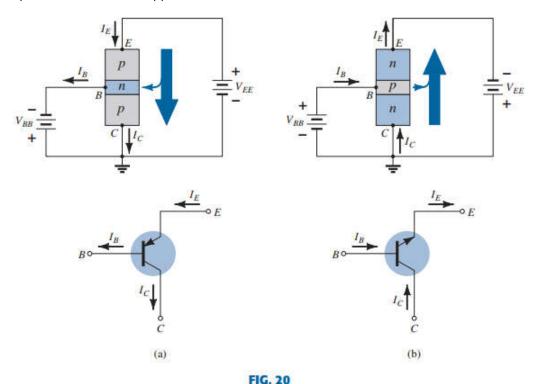
Breakdown region

As with common-B, there's a max V_{CE} that can be applied and still remain in the stable region of operation. Fig 19 has extended characteristics from fig 8 to demonstrate the impact on characteristics at high V_{CE} . At high levels of I_B the current almost climbs vertically, whereas at lower levels a region that has a weird curve due to the **negative!** resistance, where an increase in current means a decrease in voltage. It may seem weird af, but there are devices that rely on this property/characteristic. The recommended max value for a transistor under normal operating conditions is labeled BV_{CEO} or $V_{(BR)CEO}$. It's less (often 0.5 x) BV_{CBO} . For this breakdown region, there are 2 reasons for the change in curvature. One is the **avalanche breakdown** mentioned for common-B, and **punch-through, caused by Early Effect** The avalanche effect is dominant because any $\Delta I_B = \beta \cdot I_C$, which will contribute to the ionization

process during breakdown, which causes a higher ΔI_B and so on.

3.6 Common-C config

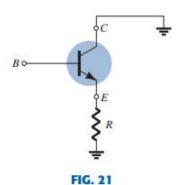
The last transistor config is the common-E config, as shown in fig 20 with proper current directions and biasing. The common-E is used primarily for impedance-matching purposes since it has high input impedance and low output impedance, opposite of common-B and common-E.



Notation and symbols used with the common-collector configuration: (a) pnp transistor; (b) npn transistor.

A common-C circuit is

shown in fig 21 with a load resistor connected from E to ground. Note that the C is tied to ground eventho the transistor is connected in a manner similar to common-E. From a design perspective, we don't need a set of common-C to choose the parameters of circuit 21. It can be designed using the common-E characteristics. For all practical purposes, the output characteristics of common-C are the same as common-E. For the common-C the output characteristics are a plot of I_E , V_{CE} for a range of I_B . The input current is the same for both common-E and common-C characteristics. The horizontal V axis for common-C is obtained by changing the sign of V_{CE} to common-E characteristics. Finally, there's a very small change in the vertical scale of I_C of the common-E characteristics if I_C is replaced by I_E for the common-E since $\alpha\approx 1$. For the input circuit of common-C the



Common-collector configuration used for impedance-matching purposes.

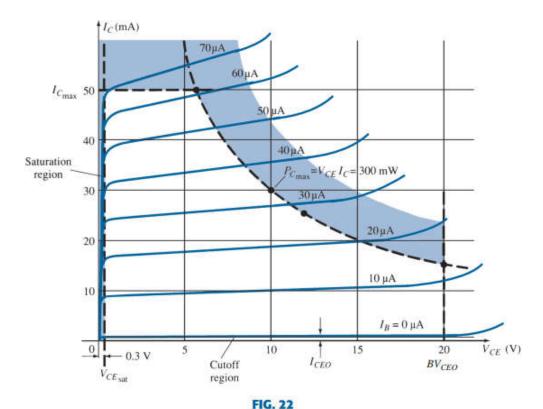
common-E base characteristics are enough to obtain the required info.

3.7 Limits of operation

For each transistor, there's a region of operation on the characteristics that will ensure that the max ratings are not exceeded and the output signal is not very distorted. This region is defined for characteristics of fig 22. All of the limits of operation are defined on a spec sheet. Some of the limits are self explanatory, such as P_{Cmax} (normally referred to as *continuous collector current*) and $BV_{CEO}, V_{(BR)CEO}$ (max collector-emitter voltage). For the transistor in FIG 22, $I_{Cmax} = 50mA, BV_{CEO} = 20V$. The vertical line on the characteristics defined as V_{CEsat} specifies the minimum V_{CE} needed without falling in the nonlinear saturation region. The level of V_{CEsat} is usually around 0.3 V. The max dissipation level is

$$P_{Cmax} - V_{CE} \cdot I_{C}$$

(17)



Defining the linear (undistorted) region of operation for a transistor.

For the one in fig 22,

(18)

 $P_{Cmax}=300mW$. To get a rough estimate of the curve, we use the V_{CE} at I_{Cmax} , at V_{CEO} and at 0.5 I_{Cmax} if the characteristic curve isn't on the spec sheet. One must simply be sure that I_C, V_{CE}, P_{Cmax} fall in the following range:

$$egin{aligned} I_{CEO} & \leq I_C \leq I_{Cmax} \ V_{CEsat} & \leq V_{CE} \leq V_{CEmax} \ V_{CE}I_C & \leq P_{Cmax} \end{aligned}$$

For common-B characteristics the max power curve is defined by

$$P_{Cmax} = V_{CB}I_{C}$$
 (19)

READ 3.8. 3.9, 3.10 yourself, not the most important section, but vaguely interesting

READ 3.8. 3.9, 3.10 yourself, not the most important section, but vaguely interesting

READ 3.8. 3.9, 3.10 yourself, not the most important

section, but vaguely interesting

READ 3.8. 3.9, 3.10 yourself, not the most important section, but vaguely interesting

READ 3.8. 3.9, 3.10 yourself, not the most important section, but vaguely interesting

3.12 Summary, finally

Important concepts

- 1. Semiconductors are better than vacuum tubes for the following reasons:
 - o smaller
 - o more lightweight
 - o more rugged
 - o more efficient
 - no warmup period
 - o no heater requirement
 - lower operating voltages
- 2. Transistors are 3-terminal devices of 3 semiconductor layers having a base sandwich layer that's thinner than the other 2. The outer 2 are either n or p type, opposite of the sandwiched type.
- 3. one p-n junction is forward biased, while the other is reverse-biased
- 4. The dc I_E is always the largest current, whereas I_B is the smallest. Also, $I_E = I_B + I_C$
- 5. The dc $I_C=$ Majority current + minority(leakage) current
- 6. The arrow in the transistor symbol defines the conventional current flow for I_E and thus defines the other current directions
- 7. A 3-terminal device needs 2 sets of characteristics to completely define it's characteristics
- 8. In the active region of a transistor, BE junction is forward-biased, while CB junction is reverse-biased
- 9. In the cutoff region, BE and CB junctions are reverse-biased
- 10. In the saturation region, BE and CB are forward-biased
- 11. On average, a good first approximation of $V_{BE}=0.7\,$
- 12. The quantity lpha relates the I_E, I_C and is always close to 1
- 13. The impedance between terminals of a forward-biased junction is always pretty small, whereas the terminals of a reverse-biased junction is very large
- 14. The arrow in the symbol of a npn points out of the device (Not Pointing iN) and points out for pnp (Pointing iN)
- 15. For linear amplification purposes, cutoff for Common-E will be defined by $I_C = I_{CEO}$
- 16. The quantity eta provides the relationship between I_B, I_C and lies between 50 and 400
- 17. The $\frac{\beta_{dc}=I_C}{I_B}$ at operating point, while β_{ac} needs a delta and is sensitive to rapid changes in curvature. They're usually close enough to substitute for each other.
- 18. To ensure that a transistor is operating within P_{max} , find $VCE \cdot I_C$ and compare to rated value

Equations

$$I_E = I_C + I_B$$
 $I_C = I_{Cmajority} + I_{Cminority}$
 $V_{BE} pprox 0.7V$
 $lpha_{dc} = rac{I_C}{I_E}$
 $lpha_{ac} = rac{\Delta I_C}{\Delta I_E} igg|_{V_{CB} = constant}$
 $I_{CEO} = rac{I_{CBO}}{1 - lpha} igg|_{I_B = 0 \mu A}$
 $eta_{dc} = rac{\Delta I_C}{\Delta I_B} igg|_{V_{CE} = constant}$
 $lpha = rac{eta}{eta + 1}$
 $I_C = eta I_B$
 $I_E = (eta + 1)I_B$
 $P_{Cmax} = V_{CE} \cdot I_C$